



# SHENZHEN TUOFENG SEMICONDUCTOR TECHNOLOGY CO.,LTD

## N-Channel Enhancement Mode Power MOSFET

3618

### 30V N-Channel MOSFET

#### PRODUCT SUMMARY

$V_{DS} = 30V$   
 $I_D = 50A$   
 $R_{DS(ON)\ TYP} = 5.8m\Omega$  ( $V_{GS} = 10V$ )  
 $R_{DS(ON)\ TYP} = 8.9m\Omega$  ( $V_{GS} = 4.5V$ )

100% UIS Tested

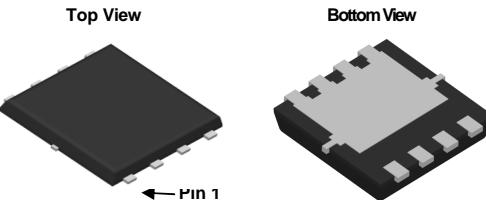
100%  $R_g$  Tested

- Trench Power  $\alpha$ MOS Technology
- Low  $R_{DS(ON)}$
- Low Gate Charge
- High Current Capability
- RoHS and Halogen-Free Compliant

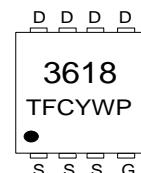
#### Applications

- DC/DC Converters in Computing
- Isolated DC/DC Converters in Telecom and Industrial

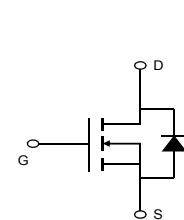
PDFN 3333



Top View



Bottom View



Y :year code W :week code

#### Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
3618	3618	PDFN3333-8	Ø330mm	12mm	4000 units

#### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>B</sup>	$I_D$ $T_C=25^\circ C$	50	A
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	150	
Continuous Drain Current <sup>A</sup>	$I_{DSM}$ $T_A=25^\circ C$	15	
Avalanche Current <sup>C</sup>	$I_{AS}, I_{AR}$	17	A
Repetitive avalanche energy $L=0.1mH$ <sup>C</sup>	$E_{AS}, E_{AR}$	23	mJ
Power Dissipation <sup>B</sup>	$P_D$ $T_C=25^\circ C$	20	W
Power Dissipation <sup>A</sup>	$P_{DSM}$ $T_A=25^\circ C$	3.1	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

#### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	$t \leq 10s$	35	°C/W
Maximum Junction-to-Ambient <sup>A</sup>		Steady-State	60	°C/W
Maximum Junction-to-Case <sup>B</sup>	$R_{\theta JC}$	5	6	°C/W



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Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$			1	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}= \pm 20\text{V}$			$\pm 100$	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.0	1.3	2.0	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	50			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=15\text{A}$		5.8	7.5	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=10\text{A}$		8.9	11	
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=15\text{A}$		30		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=15\text{A}, V_{GS}=0\text{V}$		0.75	1	V
$I_S$	Maximum Body-Diode Continuous Current				15	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		1050		pF
$C_{\text{oss}}$	Output Capacitance			195		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			150		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		2.1		$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=15\text{A}$		27.8		nC
$Q_g(4.5\text{V})$	Total Gate Charge			12.0		nC
$Q_{\text{gs}}$	Gate Source Charge			7.2		nC
$Q_{\text{gd}}$	Gate Drain Charge			9.5		nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_{\text{GEN}}=6.8\Omega$		5		ns
$t_r$	Turn-On Rise Time			3.2		ns
$t_{\text{D(off)}}$	Turn-Off DelayTime			24		ns
$t_f$	Turn-Off Fall Time			6		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=15\text{A}, dI/dt=100\text{A}/\mu\text{s}$		20		ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=15\text{A}, dI/dt=100\text{A}/\mu\text{s}$		102		nC

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$ . The Power dissipation  $P_{\text{DSM}}$  is based on  $R_{\theta JA} t \leq 10\text{s}$  value and the maximum allowed junction temperature of  $150^\circ\text{C}$ . The value in any given application depends on the user's specific board design, and the maximum temperature of  $150^\circ\text{C}$  may be used if the PCB allows it.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C: Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ .

D. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to case  $R_{\theta JC}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300ms pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ .

G. The maximum current rating is limited by bond-wires.

H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

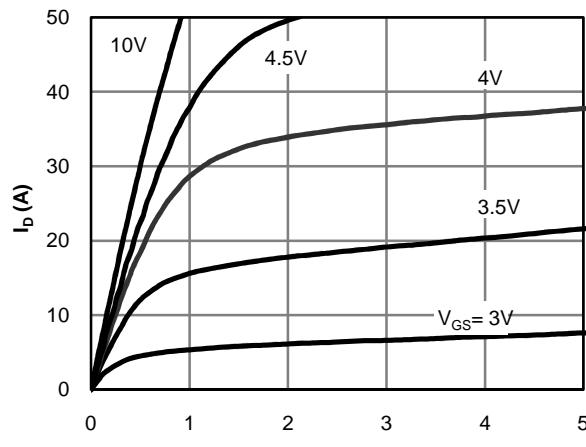


Figure 1: On-Region Characteristics

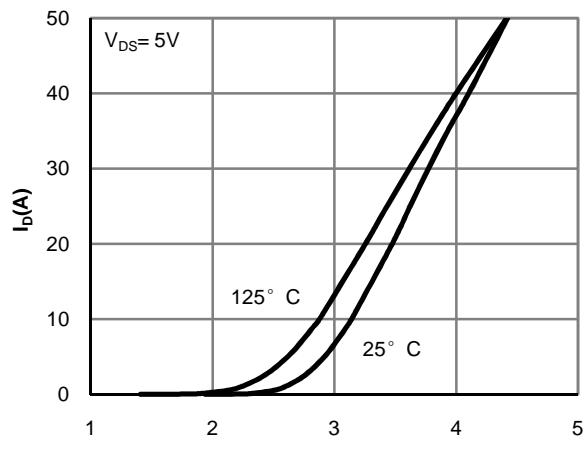


Figure 2: Transfer Characteristics

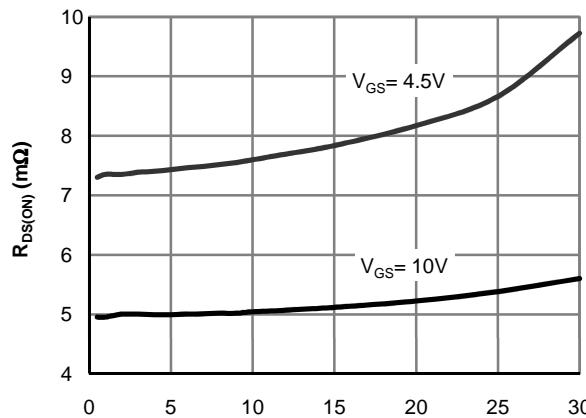


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

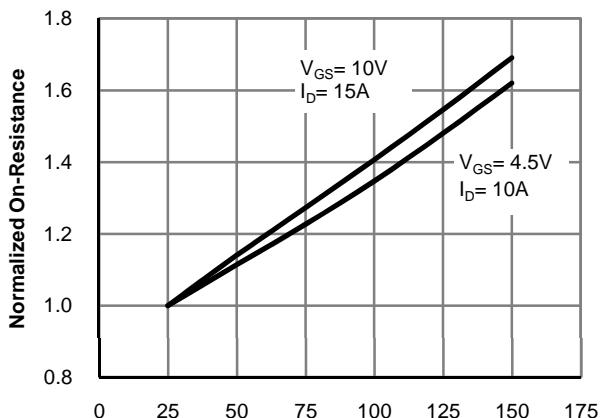


Figure 4: On-Resistance vs. Junction Temperature

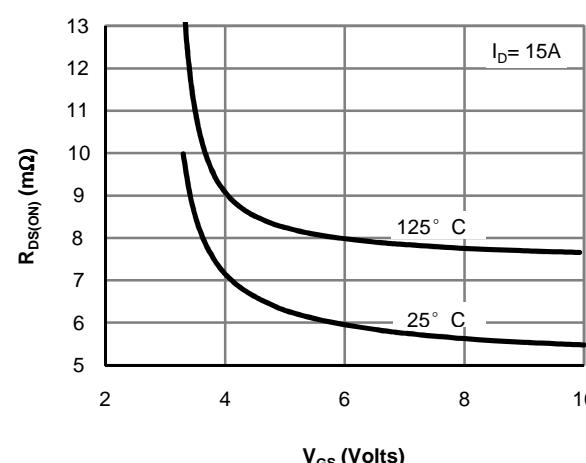


Figure 5: On-Resistance vs. Gate-Source Voltage

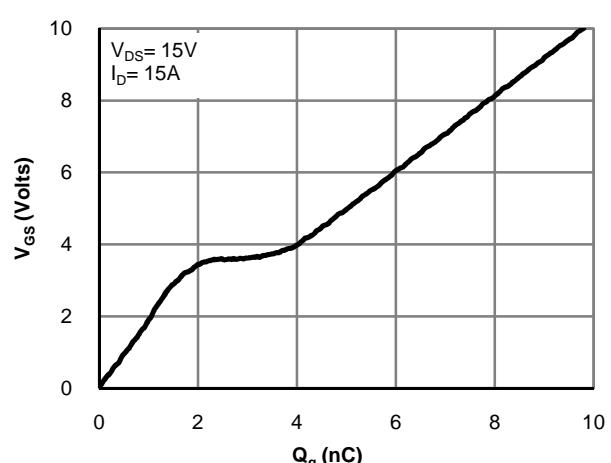


Figure 6: Gate-Charge Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

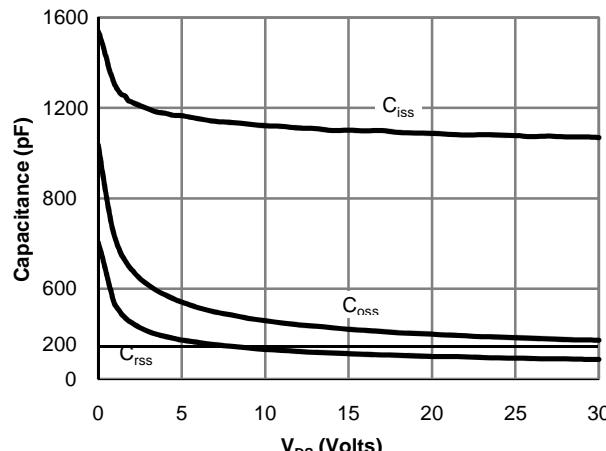


Figure 7: Capacitance Characteristics

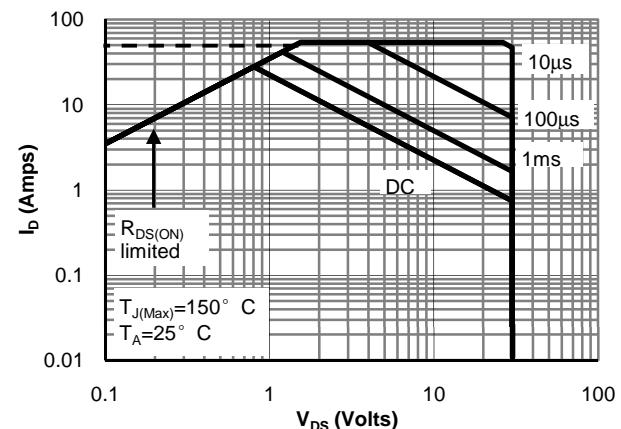


Figure 8: Maximum Forward Biased Safe Operating Area (Note H)

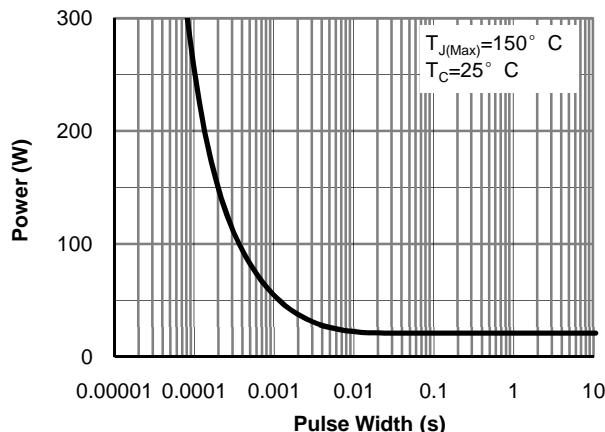


Figure 9: Single Pulse Power Rating Junction-to-Case (Note F)

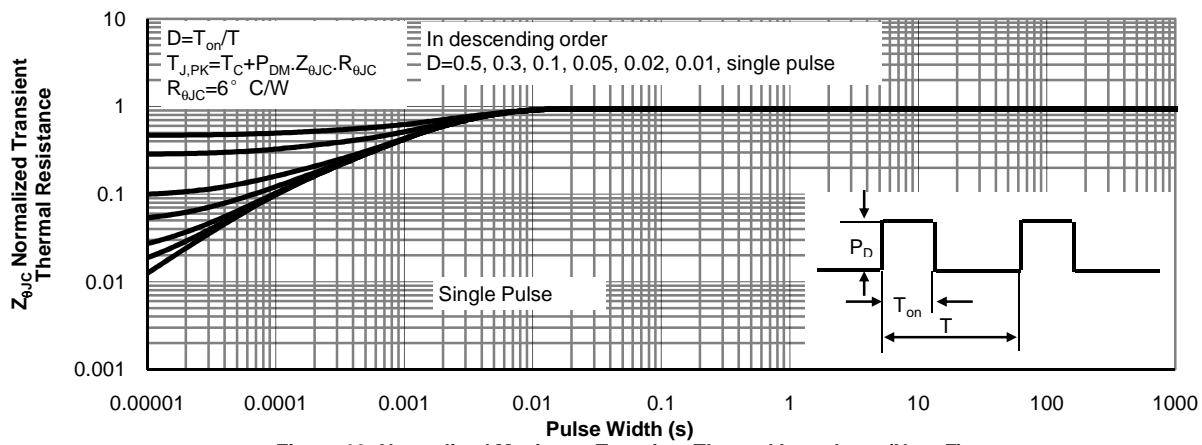


Figure 10: Normalized Maximum Transient Thermal Impedance (Note F)

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

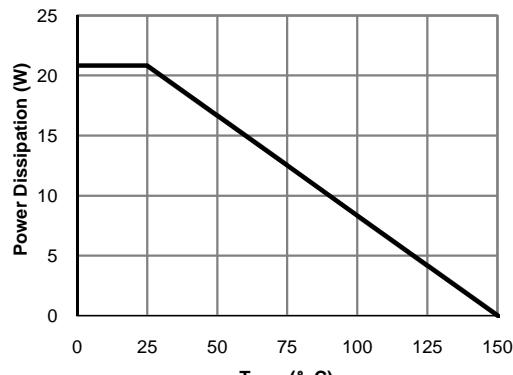


Figure 11: Power De-rating (Note F)

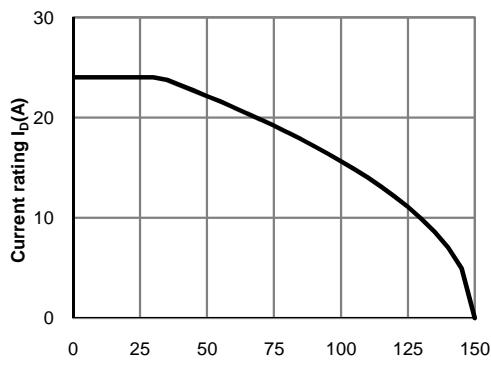


Figure 12: Current De-rating (Note F)

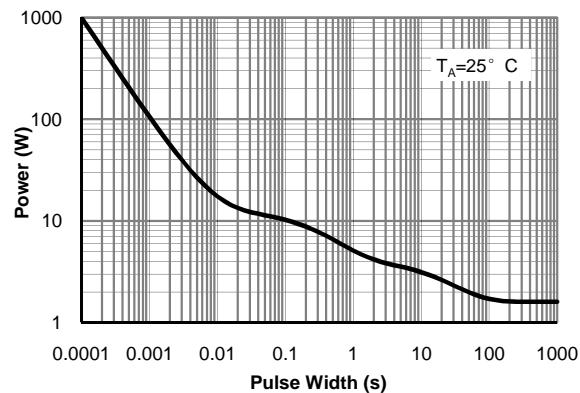


Figure 13: Single Pulse Power Rating Junction-to-Ambient (Note H)

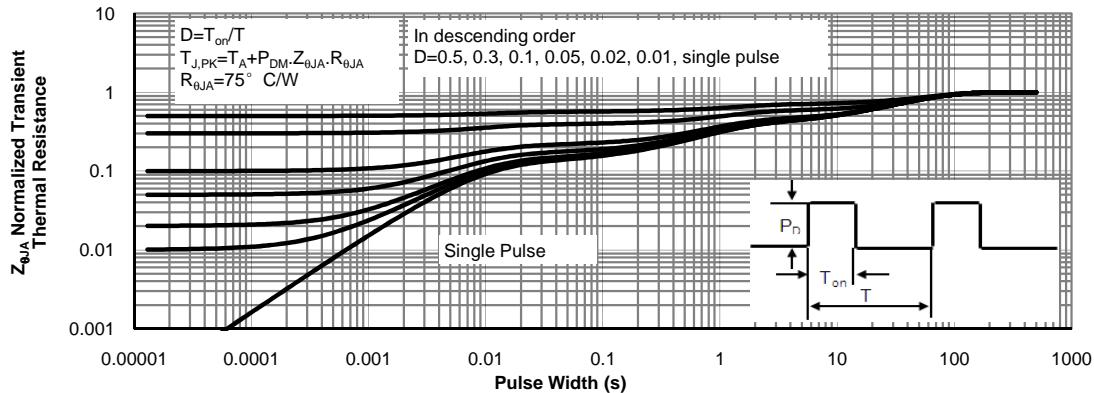
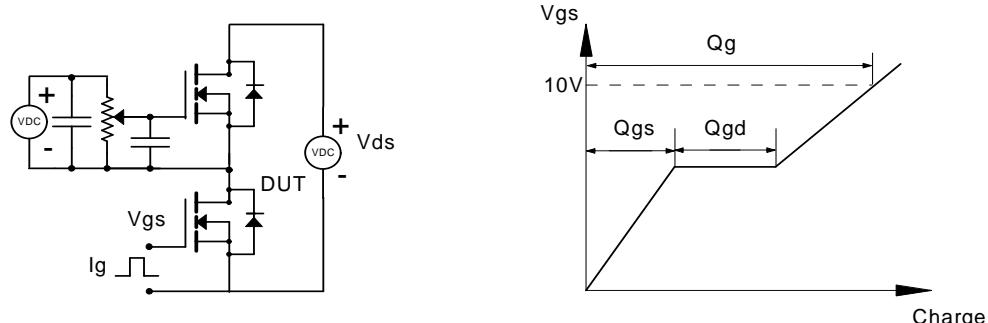
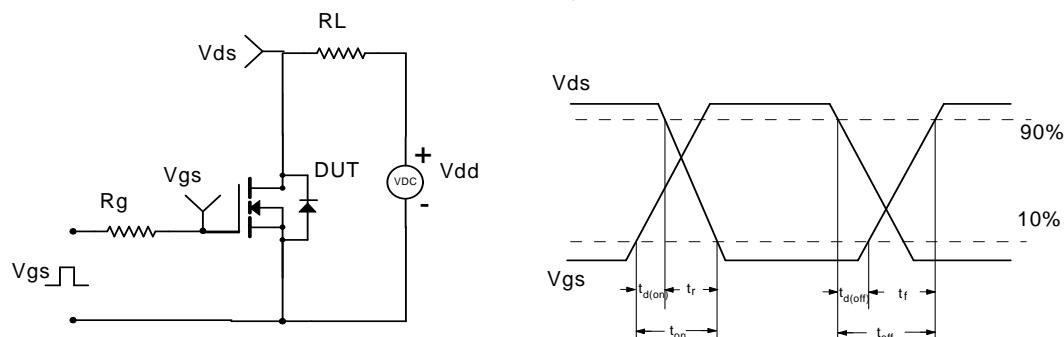


Figure 14: Normalized Maximum Transient Thermal Impedance (Note H)

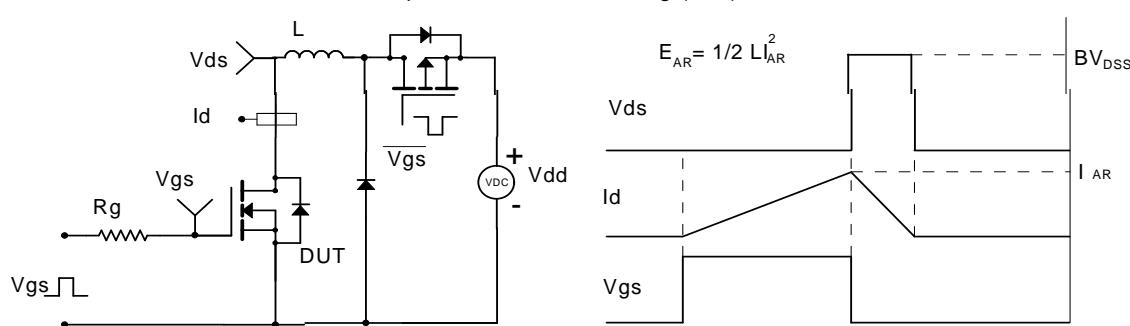
Gate Charge Test Circuit & Waveform



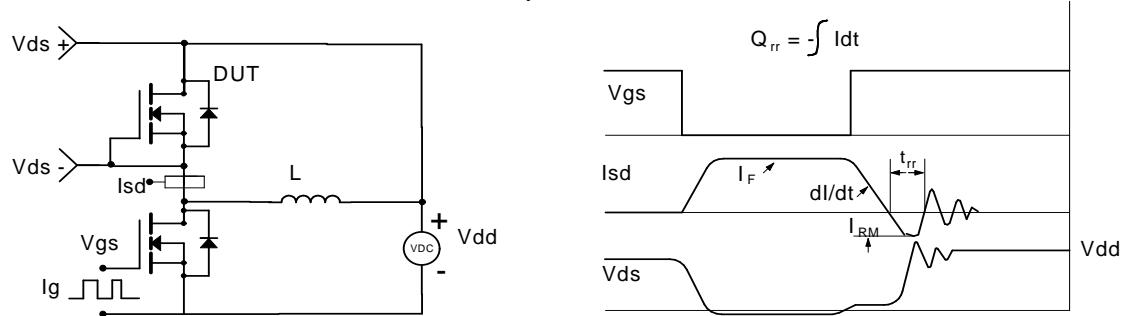
Resistive Switching Test Circuit & Waveforms



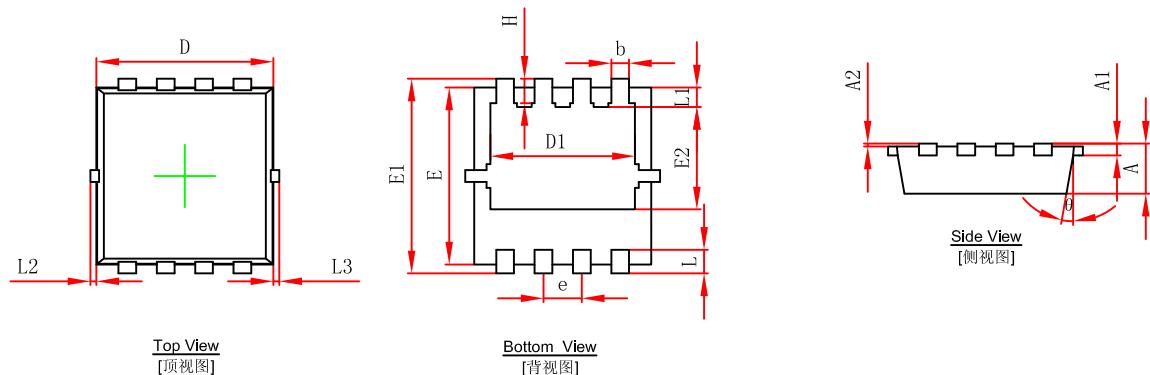
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

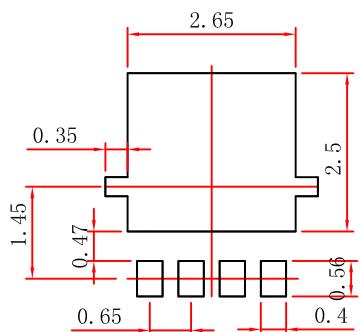


### PDFNWB3.3x3.3-8L Package Outline Dimensions



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.650	0.850	0.026	0.033
A1	0.152 REF.		0.006 REF.	
A2	0~0.05		0~0.002	
D	2.900	3.100	0.114	0.122
D1	2.300	2.600	0.091	0.102
E	2.900	3.100	0.114	0.122
E1	3.150	3.450	0.124	0.136
E2	1.535	1.935	0.060	0.076
b	0.200	0.400	0.008	0.016
e	0.550	0.750	0.022	0.030
L	0.300	0.500	0.012	0.020
L1	0.180	0.480	0.007	0.019
L2	0~0.100		0~0.004	
L3	0~0.100		0~0.004	
H	0.315	0.515	0.012	0.020
$\theta$	9°	13°	9°	13°

### PDFNWB3.3x3.3-8L Suggested Pad Layout



Note:

1. Controlling dimension: in millimeters.
2. General tolerance:  $\pm 0.05$ mm.
3. The pad layout is for reference purposes only.